



Statistical Approaches for Reliability of Future Communication Systems and Networks

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Deadline for manuscript
submissions:

closed (31 December 2021)

Message from the Guest Editors

Due to the growing interest both of academia and industry in the broad field of Reliability Engineering, for this Special Issue, we encourage high-quality research contributions—both theoretical and experimental—and timely survey papers that pinpoint future research directions in this field.

Topics of interest include, but are not limited to, the following:

- Reliability, dependability, availability, performability, serviceability, maintainability, and resiliency for emerging network and system architectures;
- Statistical methods for reliability and availability evaluation of emerging networks and systems;
- Next-generation network survivability;
- Reliability/availability aspects in the field of softwarized networks (NFV, SDN, and Network Slicing);
- Maintainability for emerging networks and systems;
- Data analysis for testbeds of emerging networks and systems;
- Prognostics and health management techniques for future networks and systems;
- Network and system resilience;
- Fault detection and isolation in large-scale networks;
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Message from the Editor-in-Chief

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